



THE AMERICAN ASSOCIATION FOR
LABORATORY ACCREDITATION

ACCREDITED LABORATORY

A2LA has accredited

DYNACAL S. DE R.L. DE C.V.
Reynosa, Tamp., Mexico

for technical competence in the field of

Calibration

This laboratory is accredited in accordance with the recognized International Standard ISO/IEC 17025:2005 *General Requirements for the Competence of Testing and Calibration Laboratories*. This laboratory also meets the requirements of ANSI/NCSL Z540-1-1994 and any additional program requirements in the field of calibration. This accreditation demonstrates technical competence for a defined scope and the operation of a laboratory quality management system (*refer to joint ISO-ILAC-IAF Communiqué dated 18 June 2005*).

Presented this 31st day of March 2008.

A handwritten signature in cursive script, reading "Peter Abney", positioned above a horizontal line.

President
For the Accreditation Council
Certificate Number 2075.02
Valid to July 31, 2009



For the calibrations to which this accreditation applies, please refer to the laboratory's Calibration Scope of Accreditation.

SCOPE OF ACCREDITATION TO ISO/IEC 17025:2005
& ANSI/NCSL Z540-1-1994

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CALIBRATION

Valid To: July 31, 2009

Certificate Number: 2075.02

In recognition of the successful completion of the A2LA evaluation process, accreditation is granted to this laboratory to perform the following calibrations¹:

I. Electrical – DC & Low Frequency

| Parameter/Equipment | Range | Best Uncertainty ^{2,3} (\pm) | Comments |
|------------------------------------|---|--|---|
| DC Voltage ⁴ – Generate | (33 to 330) mV (0.33 to 3.3) V (3.3 to 33) V (33 to 330) V (330 to 1000) V | 20 μ V/V + 1 μ V 0.013 % + 2 μ V 1.2 mV/V + 20 μ V 20 mV/V + 150 μ V 78 mV/V + 1500 μ V | Fluke 5520A/SC600 |
| DC Voltage ⁵ – Measure | (10 to 100) mV (0.1 to 1) V (1 to 10) V (10 to 100) V (100 to 1000) V (1 to 20) kV | 11 μ V/V + 0.5 μ V 10 μ V/V + 0.7 μ V 10 μ V/V + 3.5 μ V 13 μ V/V + 31 μ V 13 μ V/V + 100 μ V 410 V | Wavetek 1281FC Fluke 80K40 |

| Parameter/Equipment | Range | Best Uncertainty ^{2,3} (\pm) | Comments |
|---------------------------------------|---|---|---|
| DC Current ⁴ – Generate | (33 to 330) μ A (0.33 to 3.3) mA (3.3 to 33) mA (33 to 330) mA (0.33 to 3.30) A (3.3 to 10) A 20 A | 0.022 % + 0.02 μ A 0.012 % + 0.05 μ A 0.011 % + 0.25 μ A 0.011 % + 2.5 μ A 0.040 % + 40 μ A 0.09 % + 500 μ A 0.11 % + 750 μ A | Fluke 5520A/SC600 |
| Clamp-On Only | (20 to 550) A | 0.3 % + 0.5 A | Fluke 5520A w/coil |
| DC Current ⁵ – Measure | (10 to 100) μ A (0.1 to 1) mA (1 to 10) mA (10 to 100) mA (0.1 to 1) A (10 to 500) A | 70 μ A/A + 2.1 μ A 62 μ A/A + 2.4 μ A 65 μ A/A + 6 μ A 0.012 % + 35 μ A 0.23 % + 60 μ A 0.1 % | Wavetek 1281FC Shunts/HP 34401A |
| DC Resistance ⁴ – Generate | (1.0 to 10.9) Ω (11 to 32.9) Ω (33 to 109) Ω (110 to 329.9) Ω (0.330 to 1.09) k Ω (1.1 to 3.29) k Ω (3.3 to 10.9) k Ω (11 to 32.9) k Ω (33 to 109) k Ω (110 to 330) k Ω 330 k Ω to 1.09 M Ω (1.1 to 3.29) M Ω (3.3 to 10.9) M Ω (11 to 32.9) M Ω (33 to 109) M Ω (110 to 329) M Ω 330 M Ω to 1.1 G Ω | 0.11 % + 0.010 Ω 0.040 % + 0.015 Ω 0.018 % + 0.015 Ω 97 $\mu\Omega/\Omega$ + 0.02 Ω 44 $\mu\Omega/\Omega$ + 0.02 Ω 76 $\mu\Omega/\Omega$ + 0.2 Ω 67 $\mu\Omega/\Omega$ + 0.1 Ω 67 $\mu\Omega/\Omega$ + 1 Ω 42 $\mu\Omega/\Omega$ + 1 Ω 73 $\mu\Omega/\Omega$ + 10 Ω 61 $\mu\Omega/\Omega$ + 150 Ω 0.014 % + 150 Ω 0.05 % + 250 Ω 0.1 % + 2500 Ω 0.1 % + 3000 Ω 0.5 % + 100 k Ω 2.0 % + 500 k Ω | Fluke 5520A/SC600 Best uncertainties shown are based on 4-wire components only; for 2 wire add 5 μ V per Amp stimulus current. ($R_{\text{floor}}=E/I$) |
| Fixed Values | 1.0 Ω 10.0 Ω 100.0 Ω 1.0 k Ω 10.0 k Ω 100.0 k Ω | 0.50 m Ω 0.61 m Ω 5.8 m Ω 52 m Ω 0.52 Ω 5.3 Ω | L&N 4000-B Series |

| Parameter/Equipment | Range | Best Uncertainty ^{2,3} (\pm) | Comments |
|--------------------------------------|--|--|----------------|
| DC Resistance ⁵ – Measure | (1 to 10) Ω (10 to 100) Ω (0.1 to 1) k Ω (1 to 10) k Ω (10 to 100) k Ω (0.1 to 1) M Ω (1 to 10) M Ω (10 to 100) M Ω (100 to 1000) M Ω | 35 $\mu\Omega/\Omega$ + 50 $\mu\Omega$ 18 $\mu\Omega/\Omega$ + 0.5 m Ω 15 $\mu\Omega/\Omega$ + 0.5 m Ω 15 $\mu\Omega/\Omega$ + 5 m Ω 17 $\mu\Omega/\Omega$ + 5 m Ω 35 $\mu\Omega/\Omega$ + 2 Ω 72 $\mu\Omega/\Omega$ + 100 Ω 0.054 % rdg + 1 k Ω 0.49 % rdg + 10 k Ω | Wavetek 1281FC |

| Parameter/Range | Frequency | Best Uncertainty ^{2,3} (\pm) | Comments |
|---|--|--|-------------------|
| AC Voltage ⁴ – Generate | | | |
| (30 to 300) mV | 45 Hz to 10 kHz (10 to 100) kHz (100 to 450) kHz | 0.05 % + 8 μ V 0.1 % + 32 μ V 0.25 % + 70 μ V | Fluke 5520A/SC600 |
| (0.33 to 3.3) V | (1 to 10) kHz (10 to 100) kHz (100 to 450) kHz | 0.05 % + 50 μ V 0.1 % + 125 μ V 0.3 % + 600 μ V | |
| (3.3 to 33) V | (1 to 10) kHz (10 to 100) kHz | 0.05 % + 650 μ V 0.4 % + 1600 μ V | |
| (33 to 330) V | (1 to 10) kHz (10 to 50) kHz | 0.05 % + 10 mV 0.06 % + 10 mV | |
| (330 to 1000) V | 60 Hz to 1 kHz | 0.07 + 30 mV | |
| AC Voltage ⁵ – Measure | | | |
| (10 to 100) mV (0.1 to 1) V (1 to 10) V (10 to 100) V (100 to 1000) V | 45 Hz to 1 kHz 45 Hz to 1 kHz 45 Hz to 1 kHz 45 Hz to 1 kHz 45 Hz to 1 kHz | 0.09 % rdg + 30 μ V 0.015 % rdg + 10 μ V 0.015 % rdg + 30 μ V 0.016 % rdg + 60 μ V 0.026 % rdg + 100 μ V | Wavetek 1281FC |

| Parameter/Range | Frequency | Best Uncertainty ^{2,3,6} (\pm) | Comments |
|---|--|--|--------------------|
| Capacitance – Generate (cont) Fixed Values 0.001 μ F 0.002 μ F 0.005 μ F 0.02 μ F 0.05 μ F 0.1 μ F 0.2 μ F 0.5 μ F 1.0 μ F | 1 kHz 1 kHz 1 kHz 1 kHz 1 kHz 1 kHz 1 kHz 1 kHz 1 kHz 1 kHz | 0.0014 nF + 3.5R 0.002 nF + 3.5R 0.011 nF + 3.5R 0.015 nF + 3.5R 0.12 nF + 3.5R 0.15 nF + 3.5R 0.23 nF + 3.5R 0.97 nF + 3.5R 1.7 nF + 3.5R | GenRad 1409 Series |
| Inductance – Generate Fixed Values 10 mH 100 mH | 1 kHz 1 kHz | 0.017 mH + 3.5R 0.19 mH + 3.5R | GenRad 1482 Series |

| Parameter/Equipment | Range | Best Uncertainty ^{2,3} (\pm) | Comments |
|---|---|--|-------------------|
| Electrical Calibration of Thermocouple Indicators and Indicating Systems ⁴ – Type B Type C Type E | 600 °C to 800 °C 800 °C to 1000 °C 1000 °C to 1550 °C 1550 °C to 1820 °C 0 °C to 150 °C 150 °C to 650 °C 650 °C to 1000 °C 100 °C to 1800 °C 1800 °C to 2316 °C -250 °C to -100 °C -100 °C to -25 °C -25 °C to 350 °C 350 °C to 650 °C 650 °C to 1000 °C | 0.46 °C 0.36 °C 0.32 °C 0.26 °C 0.24 °C 0.21 °C 0.32 °C 0.50 °C 0.84 °C 0.50 °C 0.17 °C 0.15 °C 0.17 °C 0.22 °C | Fluke 5520A/SC600 |

| Parameter/Equipment | Range | Best Uncertainty ^{2,3} (±) | Comments |
|--|--|---|-------------------|
| Electrical Calibration of Thermocouple Indicators and Indicating Systems ⁴ (cont) – | | | |
| Type J | -210 °C to -100 °C -100 °C to -30 °C -30 °C to 150 °C 150 °C to 760 °C 760 °C to 1200 °C | 0.28 °C 0.17 °C 0.15 °C 0.18 °C 0.23 °C | Fluke 5520A/SC600 |
| Type K | -200 °C to -100 °C -100 °C to -25 °C -25 °C to 120 °C 120 °C to 1000 °C 1000 °C to 1372 °C | 0.36 °C 0.23 °C 0.20 °C 0.29 °C 0.44 °C | |
| Type N | -200 °C to -100 °C -100 °C to -25 °C -25 °C to 120 °C 120 °C to 410 °C 410 °C to 1300 °C | 0.40 °C 0.22 °C 0.19 °C 0.18 °C 0.27 °C | |
| Type R | 0 °C to 250 °C 250 °C to 400 °C 400 °C to 1000 °C 1000 °C to 1767 °C | 0.57 °C 0.35 °C 0.34 °C 0.40 °C | |
| Type S | 0 °C to 250 °C 250 °C to 1000 °C 1000 °C to 1400 °C 1400 °C to 1767 °C | 0.48 °C 0.92 °C 1.0 °C 0.96 °C | |
| Type T | -250 °C to -150 °C -150 °C to 0 °C 0 °C to 120 °C 120 °C to 400 °C | 0.63 °C 0.28 °C 0.20 °C 0.18 °C | |
| Type U | -200 °C to 0 °C 0 °C to 600 °C | 0.59 °C 0.3 °C | |

| Parameter/Equipment | Range | Best Uncertainty ^{2,3} (±) | Comments |
|--|---|--|-------------------|
| Electrical Calibration of RTD Indicators and Indicating Systems ⁴ | | | |
| Pt 385, 100 Ω | -200 °C to -80 °C -80 °C to 0 °C 0 °C to 100 °C 100 °C to 300 °C 300 °C to 400 °C 400 °C to 630 °C 630 °C to 800 °C | 0.05 °C 0.05 °C 0.07 °C 0.09 °C 0.1 °C 0.12 °C 0.23 °C | Fluke 5520A/SC600 |
| Pt 385, 200 Ω | -200 °C to -80 °C -80 °C to 0 °C 0 °C to 100 °C 100 °C to 260 °C 260 °C to 300 °C 300 °C to 400 °C 400 °C to 600 °C 600 °C to 630 °C | 0.04 °C 0.04 °C 0.04 °C 0.05 °C 0.12 °C 0.13 °C 0.14 °C 0.16 °C | |
| Pt 385, 500 Ω | -200 °C to -80 °C -80 °C to 0 °C 0 °C to 100 °C 100 °C to 260 °C 260 °C to 300 °C 300 °C to 400 °C 400 °C to 600 °C 600 °C to 630 °C | 0.04 °C 0.05 °C 0.05 °C 0.06 °C 0.08 °C 0.08 °C 0.09 °C 0.11 °C | |
| PtNi 385, 120 Ω | -80 °C to 0 °C 0 °C to 100 °C 100 °C to 260 °C | 0.08 °C 0.08 °C 0.14 °C | |
| Pt 385, 1 kΩ | -200 °C to -80 °C -80 °C to 0 °C 0 °C to 100 °C 100 °C to 260 °C 260 °C to 300 °C 300 °C to 400 °C 400 °C to 600 °C 600 °C to 630 °C | 0.03 °C 0.03 °C 0.04 °C 0.05 °C 0.06 °C 0.07 °C 0.07 °C 0.23 °C | |

| Parameter/Equipment | Range | Best Uncertainty ^{2,3} (\pm) | Comments |
|---|---|--|--------------------|
| Electrical Calibration of RTD Indicators and Indicating Systems ⁴ – (cont) | | | |
| Pt 3916, 100 Ω | -200 °C to -190 °C -190 °C to -80 °C -80 °C to 0 °C 0 °C to 100 °C 100 °C to 260 °C 260 °C to 300 °C 300 °C to 400 °C 400 °C to 600 °C 600 °C to 630 °C | 0.25 °C 0.04 °C 0.05 °C 0.06 °C 0.07 °C 0.08 °C 0.09 °C 0.1 °C 0.23 °C | Fluke 5520A/SC600 |
| Pt 3926, 100 Ω | -200 °C to -80 °C -80 °C to 0 °C 0 °C to 100 °C 100 °C to 300 °C 300 °C to 400 °C 400 °C to 630 °C | 0.05 °C 0.05 °C 0.07 °C 0.09 °C 0.1 °C 0.12 °C | |
| Cu 427, 10 Ω | -100 °C to 260 °C | 0.3 °C | |
| Oscilloscope Calibration ⁴ – | | | Fluke 5520A/SC 600 |
| Level Sine Wave Amplitude 50 kHz reference | 0 mV to 5.0 Vp-p | 2.3 % + 320 μ V | |
| Level Sine Wave Flatness (relative to 50 kHz) | 50 kHz to 100 MHz (100 to 300) MHz (300 to 600) MHz | 1.9 % + 100 μ V 2.0 % + 120 μ V 4.3 % + 98 μ V | |
| Squarewave Signal 50 Ω at 1 kHz Source | 100 mV, 1 V, 10 V | 1.5 % + 160 μ V | |
| Squarewave Signal 1 M Ω at 1 kHz | 100 mV, 1 V, 10 V | 1.2 % + 150 μ V | |

| Parameter/Range | Frequency | Best Uncertainty ^{2,3} (\pm) | Comments |
|---|---|---|--------------------|
| Oscilloscope Calibration ⁴ – (cont) | | | |
| Time Marker into 50 Ω Feed Through Termination | 10 ns, 100 ns 1 μ s, 100 μ s 1 ms, 100 ms | 0.3 ns 0.4 μ s 2.1 ms | Fluke 5520A/SC 600 |
| Edge Rise Time – (50 Ω Termination) | 1 kHz to 2 MHz (\geq 2 to 10) MHz | 100 ps 100 ps | |
| Distortion – Measure (-99 to 0) dB | | | |
| Fundamental Freq 20 Hz to 100 kHz | 50 Hz to 100 kHz | 2.3 db | HP 8903B |

II. Electrical – RF & Microwave

| Parameter/Range | Frequency | Best Uncertainty ^{2,3} (\pm) | Comments |
|-------------------------------------|---------------------|---|--------------------------|
| Signal Level Measuring Equipment | | | |
| (+23.98 to -56.02) dBm | Up to 20 MHz | 1.0 dB | HP 3325B |
| (+13.0 to -127.0) dBm | 100 kHz to 2000 MHz | 1.6 dB | HP 8657B |
| (-10.0 to -90.0) dBm | (2 to 18) GHz | 2.2 dB | HP 8672A |
| Power Measurements – Amplitude | (-70 to +30) dBm | 1.0 dB | HP 438A/ 8482A/ 8481D |

| Parameter/Equipment | Range | Best Uncertainty ^{2,3} (\pm) | Comments |
|------------------------------------|--|---|-----------|
| Power Meters – Readout Calibration | | | |
| Zero Set | | 0.13 mW | HP 11683A |
| Instrument Accuracy | 3 μ W 10 μ W 30 μ W (100, 300) μ W (1, 3) mW (10, 30, 100) mW | 0.037 μ W 0.12 μ W 2.1 μ W 2.9 μ W 49 μ W 1.3 mW | |

| Parameter/Range | Frequency | Best Uncertainty ^{2,3} (\pm) | Comments |
|--|-------------------|---|----------|
| Amplitude Modulation – Measure | | | |
| Rate: 50 Hz to 10 kHz, Depths: (5 to 99) % | 150 kHz to 10 MHz | 2 % of rdg + 1 digit | HP 8901B |
| Rate: 20 Hz to 10 kHz, Depths: (0 to 99)% | 150 kHz to 10 MHz | 3 % of rdg + 1 digit | |
| Rate: 50 Hz to 50 kHz, Depths: (5 to 99) % | 10 MHz to 1.3 GHz | 2 % of rdg + 1 digit | |
| Rate: 20 Hz to 100 kHz, Depths: (0 to 99) % | 10 MHz to 1.3 GHz | 3 % of rdg + 1 digit | |
| Frequency Modulation – Measure | | | |
| Rate: 20 Hz to 10 kHz, Dev.: \leq 40 kHz peak | 0.25 to 10 MHz | 2 % of rdg + 1 digit | HP 8901B |
| Rate: 50 Hz to 100 kHz, Dev.: \leq 400 kHz peak | 10 MHz to 1.3 GHz | 1 % of rdg + 1 digit | |
| Rate: 20 Hz to 200 kHz, Dev.: \leq 400 kHz peak | 10 MHz to 1.3 GHz | 5 % of rdg + 1 digit | |

III. Time & Frequency

| Parameter/Equipment | Range | Best Uncertainty ^{2,3,6} (\pm) | Comments |
|---------------------------------|------------------|---|----------------------------------|
| Frequency – Measuring Equipment | 10 MHz Reference | 6 parts in 10^{11} | Fluke 910R-GPS/ HP 5345A-Counter |
| Stopwatch/Timer | (0 to 24) hr | 0.61 s + R | HP 5345A-Counter/GPS |

IV. Mechanical

| Parameter/Equipment | Range | Best Uncertainty ^{2,6} (\pm) | Comments |
|---------------------------------|--|---|--|
| Scales | 0.5 oz to 0.5 lb (1 to 100) lb 1.0 mg to 300.0 g 4 kg | 0.0065 lb + 0.6R 0.021 lb + 0.6R 0.07 g + 0.6R 0.42 g + 0.6R | Verification with Class 6 Weights-HB44 |
| Force Gauges | (0 to 100) lbf | 0.2 lbs + 0.6R | Deadweights – Class 6 Load Frame |
| Pressure Gauges | (10 to 10 000) psig | 2.5 psi + 0.72 % rdg | PC6/EPM-700 |
| Vacuum Gauges | (0 to -12) psi | 0.56 psi + 1 % rdg | PC6 |
| Torque – Measure | (1 to 10) lbf·in (20 to 200) lbf·in (30 to 300) lbf·ft | 0.76 lbf·in 1.3 lbf·in 2.3 lbf·ft | HP-10 TSD 011/020 TSD321 |
| Torque Tester – Analog, Digital | (1 to 40) lbf·in (20 to 200) lbf·in | 0.06 lbf·in + 0.6R 0.22 lbf·in + 0.6R | Dead weight – class 6 2” & 4” torque wheel |

| Parameter/Equipment | Range | Best Uncertainty ² (±) | Comments |
|--|---------------------------------|-------------------------------------|------------------------------------|
| Indirect Verification of Rockwell Hardness Testers | HRC: Low Middle High | 1.2 HRC 1.1 HRC 1.1 HRC | Indirect verification per ASTM E18 |
| | HRB: Low Middle High | 1.8 HRB 1.2 HRB 1.1 HRB | |
| | HR30T: Low Middle High | 1.8 HR30T 1.2 HR30T 1.2 HR30T | |
| | HR45T: Low Middle High | 1.8 HR45T 1.2 HR45T 1.2 HR45T | |

V. Dimensional

| Parameter/Equipment | Range | Best Uncertainty ^{2,6} (±) | Comments |
|---------------------------|-------------|-------------------------------------|---|
| Micrometers | Up to 36 in | (130 + 20L) μin | Grade 2 gage blocks optical parallels |
| Calipers | Up to 36 in | (850 + 25L) μin | Grade 2 gage blocks gage block acc. |
| Indicators | Up to 2 in | (130 + 20L) μin | Micrometer head cal unit Grade 2 gage blocks |
| Height Gages ³ | Up to 36 in | (570 + 25L) μin | Grade 2 gage blocks |
| Depth Gages | Up to 6 in | (830 + 25L) μin | Depth master |
| Pin Gage ³ | 0 to 1 in | 61 μin | Z-Mike 1210G Class X, Y, ZZ tolerance |

| Parameter/Equipment | Range | Best Uncertainty ^{2,6} (±) | Comments |
|--|-------------------------------|-------------------------------------|--|
| Rules/Scale | Up to 12 in | 0.018 in | Master glass scales |
| Surface Plate – Flatness Repeatability | Up to 72” D (D = diagonal) | (73 + 2D) μin 67 μin | Planakator 24” & 36” Repeat-o-meter |
| Tool Makers Microscope – Linearity | Up to 2 in | (640 + 25L) μin | Master glass scales 0-2”/0-50mm |
| Optical Comparators – Linearity | Up to 12 in | (1300 + 25L) μin | Master glass scales 0-12”/0-300mm |

VI. Thermodynamics

| Parameter/Equipment | Range | Best Uncertainty ² (±) | Comments |
|---------------------|---|-----------------------------------|-------------------------------|
| Humidity | (15 to 90) % RH fixed point 33 % RH fixed point 75 % RH | 4.1 RH % 3.4 RH % 3.3 RH % | Psychrometer Salt solution |

¹ This laboratory offers commercial and on-site calibration services. This accreditation covers calibrations performed at the main laboratory listed above, and the satellite laboratory located at MAT-RGV Group, LLC, (formerly DynaCal, LLC) McAllen Foreign Trade Zone, 6620 South 33rd Street Building J Suite #25, McAllen, Texas 78503.

² “Best Uncertainty” is the smallest uncertainty of measurement that a laboratory can achieve within its scope of accreditation when performing more or less routine calibrations of nearly ideal measurement standards of nearly ideal measuring equipment. Best uncertainties represent expanded uncertainties expressed at approximately the 95 % level of confidence, usually using a coverage factor of $k = 2$. The best uncertainty of a specific calibration performed by the laboratory may be greater than the best uncertainty due to the behavior of the customer’s device, to the and to influences from the circumstances of the specific calibration.

³ On-site calibration service is available for this calibration. The uncertainties achievable on a customer's site can normally be expected to be larger than the Best Measurement Capabilities (BMC) that the accredited laboratory has been assigned as Best Uncertainty on the A2LA Scope. Allowance must be made for aspects such as the environment at the place of calibration and for other possible adverse effects such as those caused by transportation of the calibration equipment. The usual allowance for the (A2LA Cert. No. 2075.02) 03/31/2008

uncertainty introduced by the item being calibrated, (e.g. resolution) must also be considered and this, on its own, could result in the calibration uncertainty being larger than the BMC.

⁴ The measurands stated are generated with the Fluke 5500 series of instruments. This capability is suitable for the calibration of the devices intended to measure the stated measurand in the ranges indicated. In the statement of best measurement uncertainty, V , A and Ω are the appropriate quantity symbols for volts, amperes and ohms respectively. Best measurement uncertainty is read as a fraction or percentage of the output plus one-year floor specifications where defined.

⁵ The measurands stated are measured with the Wavetek 1281FC. This capability is suitable for the calibration of the devices intended to generate the measurand in the ranges indicated. In the statement of best measurement uncertainty, V , A and Ω are the appropriate quantity symbols for volts, amperes and ohms respectively. Best measurement uncertainty is based upon one-year floor specifications and is read as a fraction or percentage of the output plus range.

⁶ In the statement of best uncertainty; L is the numerical value of the nominal length of the device measured in inches; R is the resolution of the unit under test; D is the diagonal in inches.